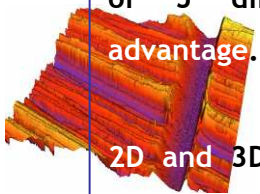


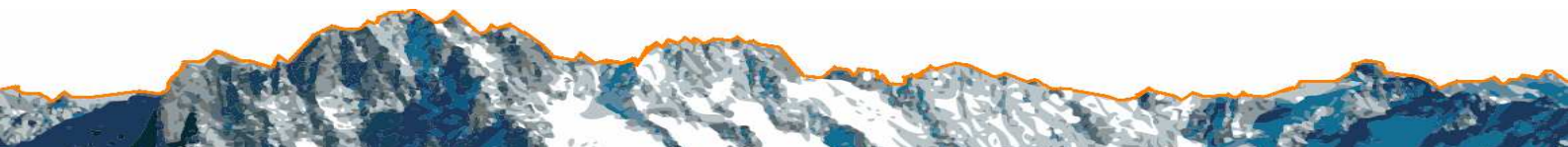
## ALTISURF<sup>®</sup> 520:

- CONTACT AND NON-CONTACT METROLOGY
- STROKE: 200x200mm
- RANGE FROM 100µm to 27mm
- VERTICAL RESOLUTION DOWN TO 5nm
- MANY SURFACE ANALYSIS TOOLS

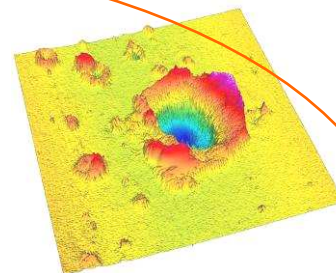
Because your company has **top-class** standards, surface characterization and topographic analysis are key factors for your **success**. With the **AltiSurf<sup>®</sup> 520**, a product specifically designed for larger samples, you can measure with or without contact along with the choice of 5 different built-in **Altiprobe<sup>®</sup>** sensors that will give you the decisive advantage.



2D and 3D surface characterization, functional parameters, 2D roughness analysis, form analysis, micro dimensions in Z, 2D or 3D form deviation, texture direction or distance measurement are just an overview of all the potential that the **AltiSurf<sup>®</sup> 520** will bring into your company.



## ALTISURF<sup>®</sup> 520



<b>General specifications</b>	
Stroke X,Y, Z (mm)	200 x 200 x 200 (motorized)
Encoder Resolution (µm)	0.5 (0.1 in option)
Profile Straightness	Up to 0.6 µm x 200 mm
Dimensions	L800 x W600 x H1000
Weight (kg)	200
Effective capacity (kg)	15
<b>PheNIX technology inside</b>	Technology developed by Altimet <sup>®</sup> on standard components basis. Allows consistent results between laboratory and production line measurements
Max. measurement speed	30 mm / s
<b>Probe</b>	<b>AltiProbe<sup>®</sup> CLA</b>
Principle	White light CLA (Chromatic Light Aberration)
Range	Large range of probes from 100 µm to 27 mm
Vertical resolution	6 to 600 nm (accuracy: 20 nm to 3µm)
Lateral resolution	up to 1.1 µm
Frequency	up to 30 KHz
<b>Probe</b>	<b>AltiProbe<sup>®</sup> Laser scanning</b>
Principle	Triangulated laser
Range	10 mm
Vertical resolution	1 µm
Lateral resolution	15 µm
<b>Probe</b>	<b>AltiProbe<sup>®</sup> Inductive</b>
Principle	Inductive pick-up with standard or specific designed styluses
Range	150 µm to 1.5 mm
Vertical resolution	2 to 60 nm
Lateral resolution	2 µm stylus radius 60° or 90° or customized
<b>Probe</b>	<b>AltiProbe<sup>®</sup> Micro Force</b>
Principle	Microforce cantilever sensor: inf. 1mg, Tungsten microprobe Ø 60µm, radius 2µm
Range	100 µm to 3 mm
Vertical resolution	5 to 75 nm
Lateral resolution	2 µm stylus radius
<b>Miscellaneous</b>	
Analysis software	Altimap <sup>®</sup> suite: Lab to line interface (control card). Self macro analysis
CCD Camera (in option)	Observation and selection of the measured zone. Zoom up to x1200

The Altisurf<sup>®</sup> 520 allows you to study the relationships between surface statements and performances -or quality- expectations (Functionality, aspect, ageing, wearing, porosity, adherence...)

Thanks to 15 years of experience on the surface metrology market, we have for core values a great knowledge of our customer's activity and the ability to efficiently meet his needs.

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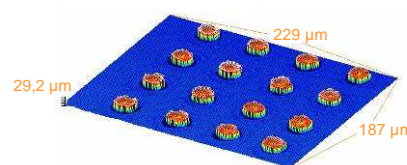
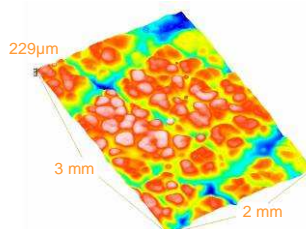
### Your Contact:

#### Altimet SAS

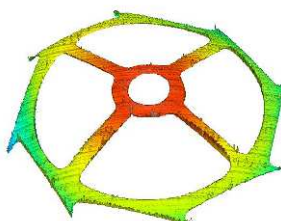
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 www.altimet.fr

### Main fields of application:

Chemistry-Material Study    Nanotech Packaging Development



Mechanical Industry



Fibrous Matress, and much more...

